



Maximum Ratings @T_A = 25°C unless otherwise specified

Cha	racteristic		Symbol	Value	Unit	
Drain-Source voltage			V_{DSS}	60	V	
Gate-Source voltage			V _{GS} ±20		V	
		(Note 3)		7.90		
Continuous Drain current	$V_{GS} = 10V$	T _A =70°C (Note 3)	I_{D}	6.30	Α	
		(Note 2)		5.36		
Pulsed Drain current	ulsed Drain current V _{GS} = 10V (Note 4)		I_{DM}	24.3	Α	
Continuous Source current (Body diode) (Note 3)			I _S	9.0	Α	
Pulsed Source current (Body diode) (Note 4)			I _{SM}	24.3	А	

Thermal Characteristics @TA = 25°C unless otherwise specified

Characteristic	Symbol	Value	Unit		
	(Note 2)		4.13 33.0		
Power dissipation Linear derating factor	(Note 3)	P _D	8.94 71.5	W mW/°C	
	(Note 5)		2.12 16.9		
Thermal Resistance, Junction to Ambient	(Note 2) (Note 3) (Note 5)	R _{θJA}	30.3 14.0 59.1	°C/W	
Thermal Resistance, Junction to Lead	(Note 6)	$R_{ heta JL}$	2.77		
Operating and storage temperature range	T _J , T _{STG}	-55 to 150	°C		

Notes:

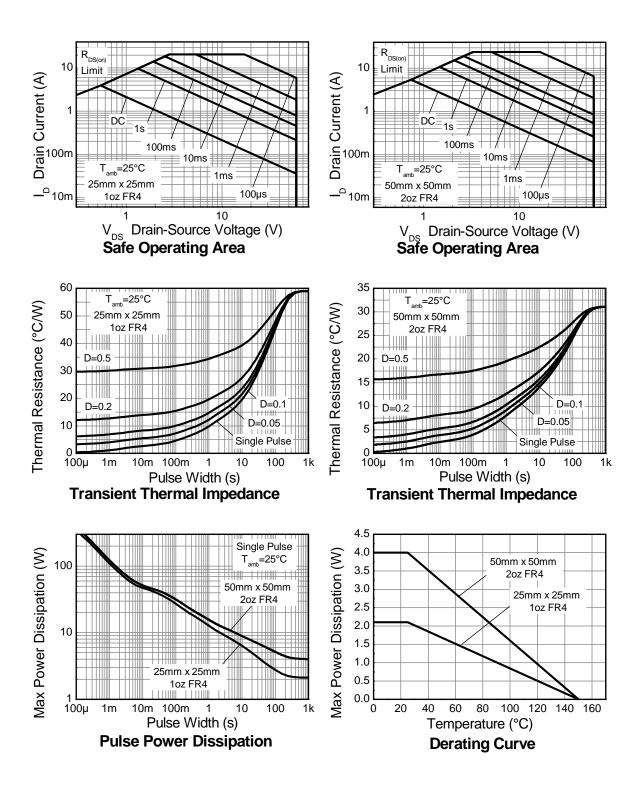
- 2. For a device surface mounted on 50mm x 50mm x 1.6mm FR4 PCB with high coverage of single sided 2oz copper, in still air conditions; the device is measured when operating in a steady-state condition.

- Same as note 2, except the device is measured at t ≤ 10 sec.
 Same as note 2, except the device is pulsed with D = 0.02 and pulse width 300 μs. The pulse current is limited by the maximum junction temperature.
 For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions; the device is measured when operating in a steady-state condition.
- 6. Thermal resistance from junction to solder-point (at the end of the drain lead).





Thermal Characteristics







Electrical Characteristics @T_A = 25°C unless otherwise specified

Characteristic	Symbol	Min	Тур	Max	Unit	Test Cor	ndition		
OFF CHARACTERISTICS									
Drain-Source Breakdown Voltage	BV _{DSS}	60	_	_	V	$I_D = 250 \mu A, V_{GS} = 0 V$			
Zero Gate Voltage Drain Current		_	_	0.5	μΑ	V _{DS} = 60V, V _{GS} = 0V			
Gate-Source Leakage		_	_	±100	nA	V _{GS} = ±20V, V _{DS} = 0V			
ON CHARACTERISTICS									
Gate Threshold Voltage	V _{GS(th)}	1.0		3.0	٧	I_{D} = 250 μ A, V_{DS} = V_{GS}			
Static Drain-Source On-Resistance (Note 7)	В		_	0.080	Ω	V _{GS} = 10V, I _D = 4.8A			
Static Dialif-Source Off-Resistance (Note 1)	R _{DS (ON)}	_		0.150	12	V _{GS} = 4.5V, I _D = 4.2A			
Forward Transconductance (Notes 7 & 8)	g fs	_	6.6	_	S	V _{DS} = 15V, I _D = 4.8	4		
Diode Forward Voltage (Note 7)	V _{SD}	_	0.88	0.95	V	I _S = 4.0A, V _{GS} = 0V			
Reverse recovery time (Note 8)	t _{rr}		19.2	_	ns	I _S = 1.4A, di/dt= 100A/μs			
Reverse recovery charge (Note 8)	Q _{rr}	_	30.3	_	nC	71S= 1.4A, di/di= 10	Α/μS		
DYNAMIC CHARACTERISTICS (Note 8)									
Input Capacitance	C _{iss}	_	459	_	pF				
Output Capacitance	Coss	_	44.2	_	pF	V _{DS} = 40V, V _{GS} = 0V f= 1MHz			
Reverse Transfer Capacitance	C _{rss}	_	24.1	_	pF				
Total Gate Charge	Qg	_	3.8	_	nC	V _{GS} = 4.5V			
Total Gate Charge	Qg	_	5.8	_	nC	V _{DS} = 30V V _{DS} = 10V I _D = 1.4A			
Gate-Source Charge	Q _{gs}	_	1.4	_	nC				
Gate-Drain Charge	Q_{gd}	_	1.9	_	nC				
Turn-On Delay Time (Note 9)	t _{D(on)}	_	2.6	_	ns				
Turn-On Rise Time (Note 9)	t _r	_	2.1	_	ns	V _{DD} = 30V, V _{GS} = 10V			
Turn-Off Delay Time (Note 9)	t _{D(off)}	_	12.3	_	ns	I_D = 1.5A, $R_G \cong 6.0\Omega$			
Turn-Off Fall Time (Note 9)	t _f	_	4.6	_	ns				

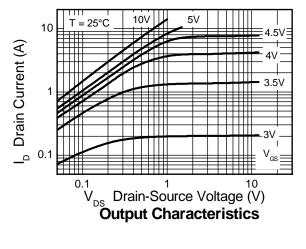
Notes:

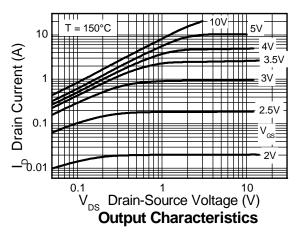
- Measured under pulsed conditions. Pulse width ≤ 300µs; duty cycle ≤ 2%
 For design aid only, not subject to production testing.
 Switching characteristics are independent of operating junction temperatures.

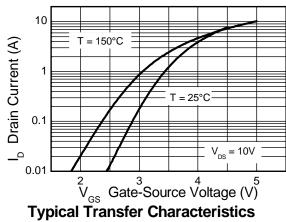


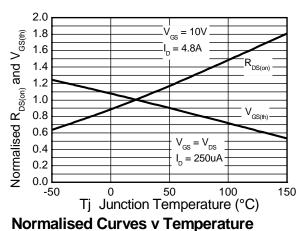


Typical Characteristics

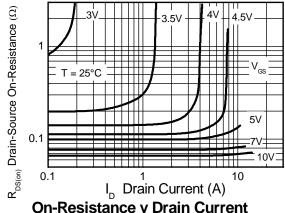


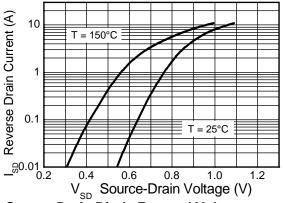






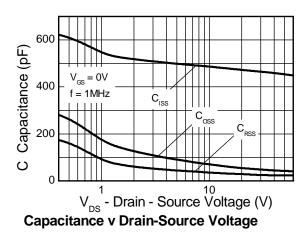


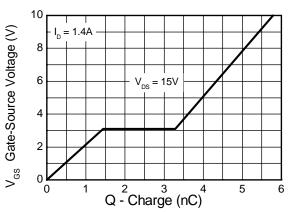






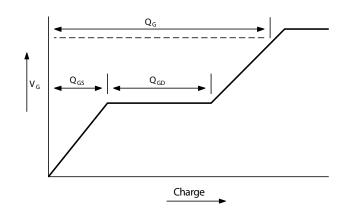
Typical Characteristics - continued





Gate-Source Voltage v Gate Charge

Test Circuits



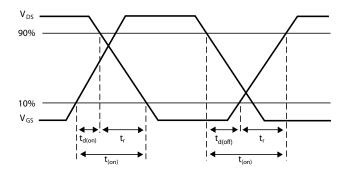
Current regulator

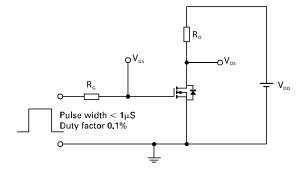
12V 0.2µF 50k Same as D.U.T

Vos

Basic gate charge waveform

Gate charge test circuit



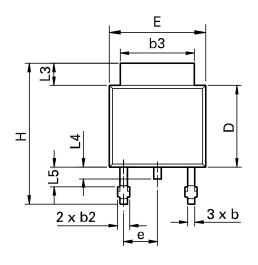


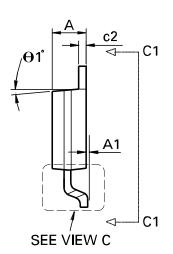
Switching time waveforms

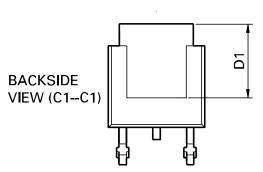
Switching time test circuit

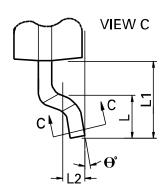


Package Outline Dimensions





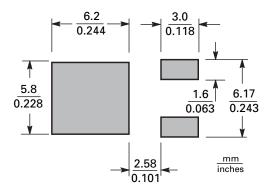




DIM	Inches		Millimeters		DIM	Inches		Millimeters	
	Min	Max	Min	Max		Min	Max	Min	Max
Α	0.086	0.094	2.18	2.39	е	0.090 BSC		2.29 BSC	
A 1	-	0.005	-	0.127	н	0.370	0.410	9.40	10.41
b	0.020	0.035	0.508	0.89	L	0.055	0.070	1.40	1.78
b2	0.030	0.045	0.762	1.14	L1	0.108 REF		2.74 REF	
b3	0.205	0.215	5.21	5.46	L2	0.020 BSC		0.508 BSC	
С	0.018	0.024	0.457	0.61	L3	0.035	0.065	0.89	1.65
c2	0.018	0.023	0.457	0.584	L4	0.025	0.040	0.635	1.016
D	0.213	0.245	5.41	6.22	L5	0.045	0.060	1.14	1.52
D1	0.205	-	5.21	-	θ1°	0°	10°	0°	10°
Е	0.250	0.265	6.35	6.73	θ°	0°	15°	0°	15°
E1	0.170	-	4.32	-	-	-	-	-	-



Suggested Pad Layout



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